nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2021 to Q4/2021

Based on structural	similarity
---------------------	------------

Supplier		User Part Number						
Nexperia B.V.		PTVS6V0S1UTR						
Name of Laboratory		Part Description						
		Nexperia DHAM	Protection					
Assembly reliability labs		SMD package						
Based on AEC-Q101 Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	286	21480	0		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	117	9360	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	86	6880	0		
# 44	remperature eyemig		1000 Cycles	00	0000	0		
	AC	JESD22-A102 Tamb = 121 °C, RH = 100 %						
# AO - It	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$		86	6000	0		
# A3 alt	Autociave	riessure – 203 kra (23.7 psia)	96 hours	86	6880	0		
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = $85 ^{\circ}$ C, RH = 85% , VR = 80% of						
# 40 alt	Temperature Reverse Bias		1000 hauna	96	6990	0		
# A2 alt	Temperature Reverse bias		1000 hours	86	6880	0		
	101	MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta T j$ =						
# A5	Intermittent Operating Life		1000 hours	n.a.	n.a.	n.a.		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat		10 s	28	840	0		
# C0		200 0 = 5 0	10.2	20	040	U		
# 610	SD Solderability	J-STD-002		26	260	0		
# C10	Solderability	3-310-002		36	360	0		

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia DHAM	Protection	9360	0	0.45	2.20E+09

© 2022 Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any nexperia.com representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.